

YieldMaxx™

Design for Manufacturing Die-Level Process Monitor (DLPM) Data Analysis Tool



Industry-Standard, High Performance Yield Analysis and Process Variation Tool

- Utilizes standard or proprietary DLPM analysis tools
- Customizable reports
- Displays die-level process-induced variance
- Performs with any process monitoring tools
- Expedites problem resolution
- Insignificant processing latency
- Operates in Windows
- Multi-configurable input format
- Provides support code

General Description

The quick identification and correction of yield problems is an imperative issue that can be simply solved by YieldMaxx. Interfacing through an API with independent die-level process monitoring tools, YieldMaxx integrates large volumes of disparate data to provide accurate yield analysis in a matter of minutes. The user is able to correct the disparity faster due to an automated test equipment database.

The software analyzes and presents standard on-die, parametric data measurements of key performance parameters, such as threshold voltage, resistance, and capacitance. With a friendly GUI, YieldMaxx displays visual indications of device mismatch parameters, as shown in Figure 1.

YieldMaxx allows foundries, IDMs, or design houses to rapidly analyze critical process control monitor parameters to sort and display them for quick interpretation and yield-related trade-off decisions.

Additional Information

Ridgetop offers IC integration technical support to assist customers at every step in the process.

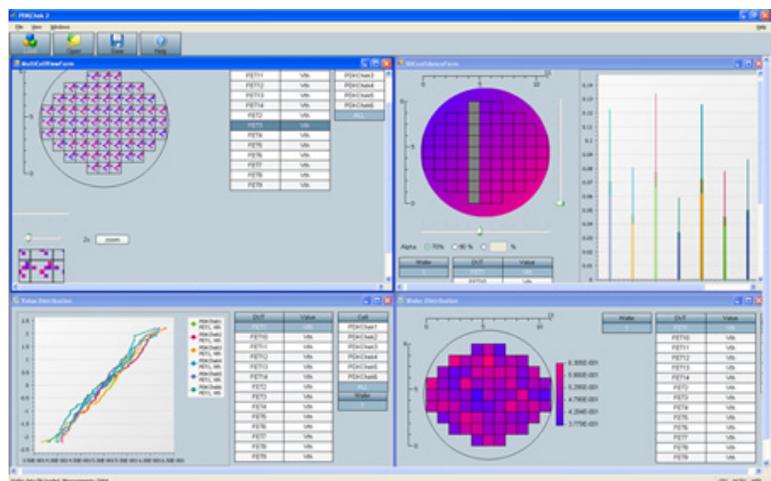


Figure 1: YieldMaxx graphical utility

Our design team has extensive experience in CMOS and bipolar IC design semiconductor process technologies, and practical, results-oriented engineering.

The Market

YieldMaxx can run large disparate inputs at insignificant processing latencies.

With a variety of standard analysis tools, the software provides ample and accurate yield information. YieldMaxx is highly sought-after for its speed, facilitation of testing, and provided customer support.

The Opportunity

With the growth in the semiconductor industry and the years to date from the initial implementation of yield analysis software, companies will be ready for improvements in process design monitoring tools and software.

The desire for rapid capture of yield loss and a high return on investment are applicable for all fabless, foundry, IDM, and photovoltaic companies.

About Ridgetop

Ridgetop Group Inc. is the world leader in providing advanced electronic prognostics and health management (PHM) solutions, semiconductor IP blocks, and built-in self-test (BIST) solutions for critical applications.

Ridgetop was founded in 2000 with the purpose of introducing revolutionary tools to improve performance of mission-critical electronic systems.

With a strong management team and world-class technical staff, Ridgetop has established a stellar reputation serving its government and commercial customers with "best of class" solutions.

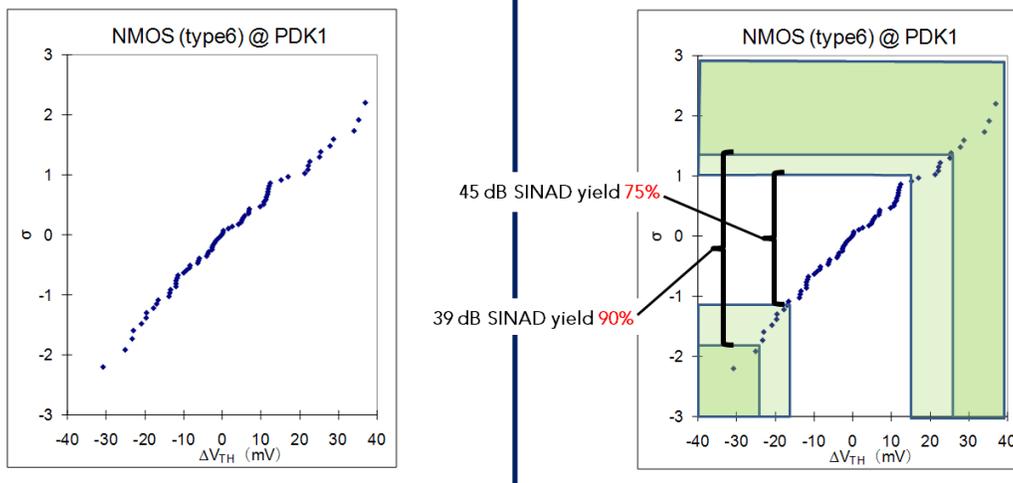


Figure 2: Representative data are collected and displayed on the left; YieldMaxx allows quick analysis of the data to provide trade-offs of acceptable signal-to-noise versus yield

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Corporate Headquarters

3580 West Ina Road
Tucson, Arizona 85741 USA
OFFICE +1 520 742 3300
INFO@RIDGETOPGROUP.COM

Worldwide Locations

Support and sales locations for Ridgetop Group Inc. exist in Germany, Belgium, Japan, China, and the United States.
For office locations and contact information, please call the corporate headquarters or visit us on the web: www.ridgetopgroup.com